Sem-'VIII

ETRX (CBGS)

CMOS VLSI Design

Q.P. Code: 719703

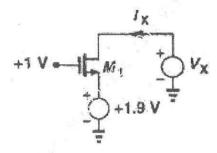
(3 Hours)

Total Marks: 80

Note:1) Question ONE is compulsory

- 2) Solve any THREE out of remaining questions
- 3) Draw neat and clean diagrams
- 4) Assume suitable data if required.

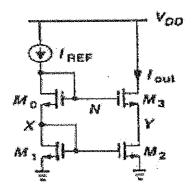
1.	A.	Establish the appropriate relationship between g _m and R _{on} for MOSFET.	5
	В.	Draw and explain LC oscillator.	5
	C.	Explain the necessity of Millers theorem with suitable example.	5
	D.	Explain System on chip and System in package.	5
2.	A.	What is bandgap reference? In short describe various methods of	10
		implementation of bandgap references.	
	В.	Draw and explain common gate circuit.	5
	C.	Sketch lx and the transconductance of the transistor as a function of Vx for	5
		each circuit in the given figure as Vx varies from 0 to VDD. For part (a)	
		assume Vx varies from 0 to 1.5V.	



- 3. A. Write qualitative analysis of input-output characteristics of a differential pair. 10 Also mention about common mode characteristics for the same.
 - B. Write in detail about speed considerations of a switch capacitor circuit.

4. A. In the following Figure, sketch V_x and V_y as a function of I_{REF} . If I_{REF} requires 0.5V to operate as a current source, what is its maximum value? Assume: for all transistors

(W/L)=25/0.5, $\mu_{_{D}}C_{_{OX}}=50~\mu\text{A/V}^2, V_{_{TH}}=0.6\text{V}, \lambda=\gamma=0~\text{and}~V_{_{DD}}=3\text{V}.$



5 Explain the following for op-amp В. II. Input Range Limitation I. CMRR 5 Explain the white noise and flicker noise in case of MOSFET. Explain which C. noise is dominant when? 10 Discuss stability issues and frequency compensation of two stage operational 5. A. amplifier. 10 Explain Non-ideal effects in PLL. В. 5 6. A. Compare the performance of various op-amp topologies. 5 B. Draw and explain charge pump circuit. 5 Explain noninverting switched capacitor amplifier circuit. C. 5 Draw and explain AMS design flow. D.

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16/12/2016

Q.P. Code: 733703

(3 Hours)

			(S.Hours)	Liotai Marks: 80
N.	В.:	(1) Q1	uestion No.1 is compulsory.	
		(2) Sc	olve any three from remaining.	20 20 21 November 20
1.	So	olve any	y four :	20
		(a	a) Write a short note on frame relay.	, b/V
		(b	b) What do you mean by Network layer design?	
		(c	c) What is wireless sensor network?	10
		(d	d) Explain with diagram frame format of SO NET.	<u> </u>
			e) What is Roll of VCI & VPI in ATM?)
2.	(a)	What is	a firewall? What are the capabilities & limitation of fi	rewall? Discuss 10
			ferent type of firewall, along with their advantage &	
	(b)		the hardware implement of SONET auchitecture.	10
3.	(a)	Explair	the protocol stack for IEEE 802,95.1 standard.	10
	(b)	Draw a	nd explain IEEE 802.15.4 LR-WPAN device archi	tecture. 10
4.	(a)		n ATM cell format. Also describe the different func	tional layers of 10
		ATM a	nd bring out the significance of AAL layer.	
			ind explain frame format of FR & explain address	s fields. How it 10
			es congestion control and QoS.	
5.	(a)	Explain	Demilitarized Zone (DMZ) in brief.	10
	(b)	What is	the need of DWDM? Explain the technology with a	neat schematic 10
			n, also list the system components.	
			Der g	
6.	W		nortmote (any four):	20
			MON and FCAPS	
		(b) Pa	cket filtering	
		(c) B-		
	y**.	(\mathbf{d}) NA		
		(e) Po	ort forwarding	



		3 Hours	
		N.B.	
	1)	Q. No. 1 is compulsory.	
	2)	Attempt any three out of remaining questions.	
	3)	Assume any suitable data wherever required but justify the same.	
1	а	Justify the statement that silicon based microelectronics is different than micro-	20
		fabrication (MEMS fabrication).	
	b	State various Chemical Vapor Deposition Techniques. Explain in brief any one	
		of the techniques of Chemical Vapor Deposition for MEMS device fabrication.	
	С	Define Piezo-resistive property of single crystal silicon as MEMS material. Also	
		define and justify that semiconductor material has high Gauge factor.	
	d	What is the resonant frequency Fo for the silicon cantilever beam of 2000µm	
		long and 200 μ m wide and 1.5 μ m thick?(Data : for silicon E = 190 GPa and The	
		density is 2.39 g/cm³)	
2	а	Explain transduction pertaining to capacitive measurement, Piezo-resistive for	10
		MEMS. Also state different parameters on which this transduction depend.	
	b	Discuss fabrication process for DMD. Justify clearly choice of material, process	10
		parameters & sub-type of processes preferred	
3	а	Justify the need of vacuum pressure in Physical Vapor Deposition (PVD).	10
		Explain in brief any one of the techniques of PVD for MEMS device fabrication.	10
		Also define the terms step coverage and shadowing.	
	b	Describe the representative process flow for fabricating the micro-heater. Also	
		explain the operating principle of this MEMS device in detail with its analytical	
		expression.	1000
4	a	• IM	10
	b	Give two examples of combination of structural, sacrificial layers and enchants	10
		used in MEMS fabrication along with their applications	
5	а		10
		What are the different types of Wafer bonding?	
	b	Discuss MEMS reliability in detail.	10
6		Write a short note on (any three)	20

Plasma Etching

High Aspect Ratio MEMS DMD (Digital Mirror Device)

b

Advantages and limitations of surface micromachining



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ETRX (CBG)

Sem-VIII

Mobile Communication

QP Code: 728301

			(3	Hours)	[Total Marks	:80
N.	В.;	(1) (2) (3)	Question No. 1 is compulsor Attempt any three questions Assume suitable data whereve	out of the remaining five qu	iestions.	
1.	Ans	(a) V (b) Z (c) I (d) I	Iny four of the following: What is meant by term umbrella of A large city with an area of 1500 in the following of 2 medius of 3 medius of	km ² is needed to be covered b km each. How many cell sites hal shaped cells? MA and FDMA. tegies from IG to 3G.	y a finite would be	5 5 5 5
2.	(a) (b)	What	nin the GSM network architecture is frequency reuse? How does it advantage of frequency reuse?	with a neat block diagram, influence the co channel inter	ference? What	10 10
3.		Compreuse,	ectrum of 30 MHz is allocated to a 5 kHz simplex channels to provide the number of channels available, b) seven cell reuse, c) 12 cell repare GSM and CDMA technologic	le fall duplex voice and contro lable per cell if a system uses, suse and d) 13 cells reuse.	ol channels.	10
4.	(a) (b)	Expla What	nin IS-95 forward and reverse char is WCDMA air interface? Give i	nnels. mportant parameters of it.		10 10
5.	(a) (b)	Descr Write	ribe UMTS technology with a nea a detailed note on LTE.	t block diagram.		10 10
ó.		te sho (a) (b) (c)	rt notes on any four of the follow Wireless sensor networks Speech coding in GSM Mobile IP	ving:		5 5 5

(e)

WiMax



ETRX ((BU)

Robotics

Sem-UIII

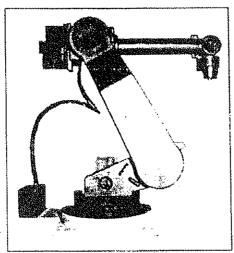
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(3 Hours)

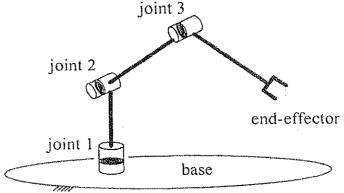
[Total Marks: 80]

1. Question No. 1 is compulsory.

- 2. Attempt any three questions from the remaining five questions.
- 3. Assume suitable data if necessary.
- 4. Figures to the right indicate full marks.
- Q.1. Answer following questions in brief.
 - Draw the approximate workspace for the following robot. Assume the (05)dimensions of the base and other parts of the structure of the robot are as shown below.



- b What is a homogeneous transformation matrix? Give the transformation (05)matrix for pure translation and rotation matrix about y-axis.
- (05)Discuss wave-front planner in brief.
- d What is Histogram? Explain the use of Histogram in image processing. (05)
- A 3-DOF robot arm has been designed for applying paint on flat walls, as (12)Q.2. shown below.

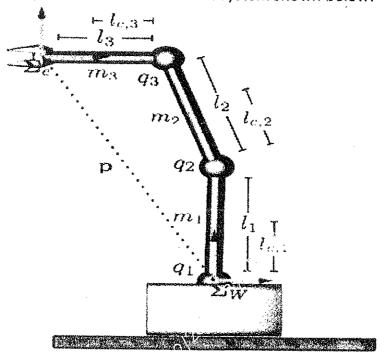


- D-H Assign coordinate frame as necessary based on representation
- Write parameter table
- Find the UTH matrix.

[TURN OVER

b	Define the following terms	(08)
	 Roll, Pitch and Yaw angles 	(00)
	• Euler angles	
	 Articulated joints 	
a	Discuss differential rotation about reference axes.	(08)
b	Derive the equations of motion for the system shown below:	(12)

Q.3.



Q.4.	the first of the f	(10) (10)
Q.5.	h Differentiate between	(10) (10)
Q.6.	b Robot applications c Potential function in non-Euclidean spaces	(05) (05) (05) (05)